


Search Notes 	Application No.	Applicant(s)	
	09/624,014	SAKAGUCHI, HIDEAKI	
	Examiner	Art Unit	
	Mary Kate B Baran	2857	

SEARCHED			
Class	Subclass	Date	Examiner
702	57-59	2/3/2004	MCB
702	64-65	2/3/2004	MCB
702	117-118	2/3/2004	MCB
702	124	2/3/2004	MCB
702	126	2/3/2004	MCB
702	183	2/3/2004	MCB
702	189	2/3/2004	MCB
324	512	2/3/2004	MCB
324	522-523	2/3/2004	MCB
324	527	2/3/2004	MCB
324	537	2/3/2004	MCB
324	763-765	2/3/2004	MCB
324	770	2/3/2004	MCB

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
702	117	2/3/2004	MCB
324	523	2/3/2004	MCB

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Text Search: semiconductor, DUT, device under test, IC, integrated circuit, D/A converter, digital to analog converter	2/3/2004	MCB
EAST Text Search (con'd): voltage range, output, input, range	2/3/2004	MCB